

Bayesian Reliability Analysis: Statistical Challenges from Science-Based Stockpile Stewardship

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Acknowledgments

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Surveillance Transformation

Develop and advance the analytical capabilities required to perform computational predictions of stockpile performance, reliability, end-of-life, safety, survivability, use control; and to provide risk-based responsiveness for future replacement and refurbishment decisions.

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- ▶ Uncertainty quantification

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- ▶ Uncertainty quantification
- ▶ Planning

B61 Case Study: Block Diagrams

Bayesian
Reliability Analysis

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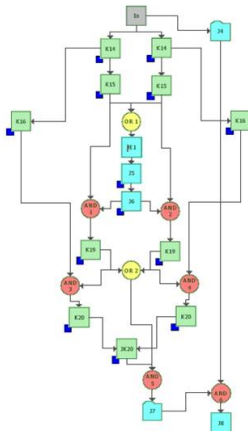
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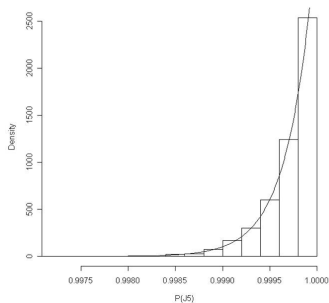
System Reliability Equation

$$\begin{aligned} R_{SYS} = & R_{JK20}R_{J7}R_{J4}R_{J8}R_{JE1}R_{J5}R_{J6}(\\ & R_{K14(1)}R_{K14(2)}R_{K16(1)}R_{K16(2)}R_{K20(1)}R_{K20(2)}R_{K15(1)}R_{K15(2)}R_{K19(1)}R_{K19(2)} \\ & - R_{K14(1)}R_{K14(2)}R_{K16(1)}R_{K16(2)}R_{K20(1)}R_{K20(2)}R_{K15(2)}R_{K19(2)} \\ & - R_{K14(1)}R_{K14(2)}R_{K16(1)}R_{K16(2)}R_{K20(1)}R_{K20(2)}R_{K15(1)}R_{K19(1)} \\ & - R_{K14(1)}R_{K14(2)}R_{K16(1)}R_{K20(1)}R_{K15(1)}R_{K15(2)}R_{K19(1)}R_{K19(2)} \\ & - R_{K14(1)}R_{K14(2)}R_{K16(2)}R_{K20(2)}R_{K15(1)}R_{K15(2)}R_{K19(1)}R_{K19(2)} \\ & + R_{K14(1)}R_{K14(2)}R_{K16(1)}R_{K20(1)}R_{K15(2)}R_{K19(2)} \\ & + R_{K14(1)}R_{K14(2)}R_{K16(2)}R_{K20(2)}R_{K15(1)}R_{K19(1)} \\ & + R_{K14(1)}R_{K16(1)}R_{K20(1)}R_{K15(1)}R_{K19(1)} \\ & + R_{K14(2)}R_{K16(2)}R_{K20(2)}R_{K15(2)}R_{K19(2)}) \end{aligned}$$

Overview of Methodology

- ▶ Estimate reliability for each component
 - ▶ Point estimate
 - ▶ Measure of uncertainty (credible interval)
- ▶ Combine component reliability distributions using Monte Carlo to get system reliability distribution

No failures in 3513 tests

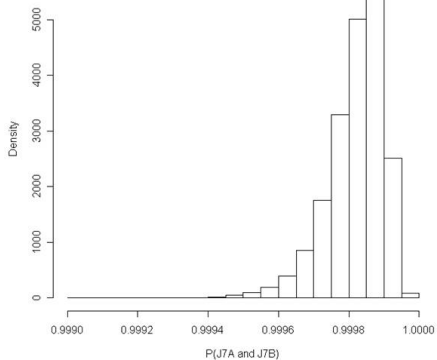


Data on components and collections of components

- ▶ Data J7A: 383 variables measurements.
Requirement($-4.5, 4.5$)
- ▶ Data J7B: 468 variables measurements.
Requirement($-3.8, 3.8$)
- ▶ There are 383 tests with both measurements, and 85 with only the measurements of J7B.
- ▶ In addition, we have the 2327 pass/fail tests that insure that both J7A and J7B were within the requirements. This count includes the 468 tests described above.

$$\prod_{i=1}^{383} \frac{1}{\sigma_A} \exp\left(-\frac{1}{2\sigma_A^2}(x_i - \mu_A)^2\right)$$
$$\prod_{j=1}^{468} \frac{1}{\sigma_B} \exp\left(-\frac{1}{2\sigma_B^2}(y_j - \mu_B)^2\right)$$
$$\left(\left(\Phi(4.5, \mu_A, \sigma_A) - \Phi(-4.5, \mu_A, \sigma_A)\right)\right. \\ \left. \left(\Phi(3.8, \mu_B, \sigma_B) - \Phi(-3.8, \mu_B, \sigma_B)\right)\right)^{1859}$$

Posterior



Assurance Testing Example

- ▶ Six previous systems with similar components
- ▶ Each previous system had 20 tests done
- ▶ Temperature ranges from 30° to 70°
- ▶ Chemistry parameter ranges from 0 to 1
- ▶ Approximately 15% of the data is right-censored
- ▶ Simulated data

More on the Example

- ▶ Interest in developing a replacement component
- ▶ “Life extension program”
- ▶ Two ways to think about lifetime
 - ▶ Time since built
 - ▶ Time in use
- ▶ Six previous systems with similar components
- ▶ Temperature and “chemistry parameter” predictive of lifetime

Reliability Demonstration and Assurance

- ▶ Example: Using minimal assumptions, to demonstrate that reliability at time t_0 hours is .99, with 90% confidence, requires testing at least 230 units for t_0 hours with zero failures. To have a 80% chance of passing the test, requires that the true reliability be approximately .999.
- ▶ For complicated, expensive systems, traditional reliability demonstration is usually not practical
- ▶ Reliability assurance is the alternative: Use whatever relevant knowledge you have in a principled Bayesian approach to plan the test

What Test Plan?

Denote the test plan (n, t_0, c) .

- ▶ How many of the new components (n) should I test?
- ▶ For how long (t_0)?
- ▶ How many can fail (c)?

Test Criteria

Interest centers on $t = 1$

- ▶ Posterior Producer's Risk: Choose a test plan so that if the test is failed, there is a small probability that the reliability at $t = 1$ is high
- ▶ Posterior Consumer's Risk: Choose a test plan so that if the test is passed, there is a small probability that the reliability at $t = 1$ is low
 - ▶ Reliable Life Criterion: Choose a test plan so that if the test is passed, there is a high probability that the $1 - \alpha$ quantile of the distribution is greater than $t = 1$

- ▶ Fit the data using a Weibull regression
- ▶ Common shape parameter β
- ▶ Scale parameter λ_{ij}
 - ▶ $i = 1, \dots, 6, j = 1, \dots, 20$
 - ▶ $\log(\lambda_{ij}) = \gamma_0 + \gamma_1 \text{Temp}_{ij} + \gamma_2 \text{Chem}_{ij} + \gamma_3 (\text{Temp} \times \text{Chem})_{ij} + \omega_i$
 - ▶ Common regression model with hierarchical “random effect” ω_i for each system
- ▶ $\omega_i \sim N(0, \tau_\omega)$
- ▶ Diffuse priors for $\gamma_0, \gamma_1, \gamma_2, \gamma_3, \tau_\omega, \beta$

More on the Example

- ▶ Assume the new system follows the common regression model with its own parameter ω_N
- ▶ Choose a test plan (n, t_0, c) so that given the previous data, if the test is passed, there is a 0.9 probability that the 0.05 quantile of the distribution when Temp = 50° and Chem = 0.5 is greater than $t = 1$
- ▶ Choose $c = 0$ so that the test is passed only if there are no failures
- ▶ $q_{0.05} = \lambda^{-1/\beta}[-\log(0.95)]^{1/\beta}$

Computation

$$\mathbf{P}(q_{0.05} > t_{R^*} = 1 \mid TIP, \mathbf{t})$$

Computation

$$\begin{aligned} \mathbf{P}(q_{0.05} > t_{R^*} = 1 \mid TIP, \mathbf{t}) \\ = \mathbf{P}(\lambda < -\log(0.95)t_{R^*}^{-\beta} \mid TIP, \mathbf{t}) \end{aligned}$$

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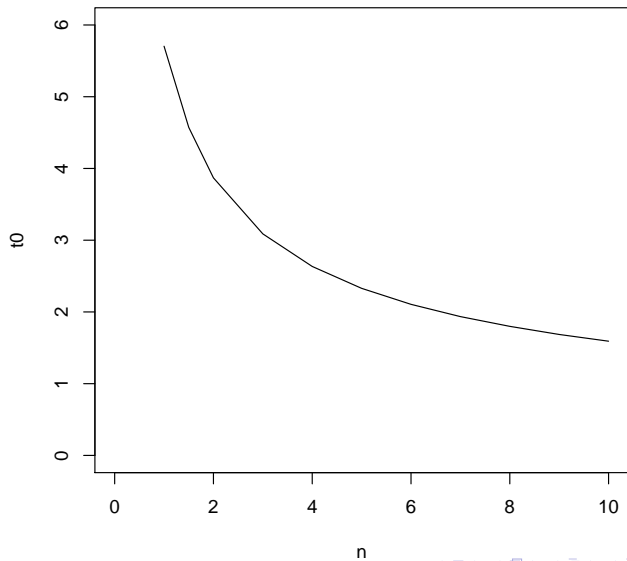
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Monte Carlo Approximation

$$\begin{aligned} & \mathbf{P}(q_{0.05} > 1 \mid TIP, \mathbf{t}) \\ &= \frac{\int_0^\infty \int_0^{-\log(0.95)} \exp(-n\lambda t_0^\beta) p(\lambda, \beta \mid \mathbf{t}) d\lambda d\beta}{\int_0^\infty \int_0^\infty \exp(-n\lambda t_0^\beta) p(\lambda, \beta \mid \mathbf{t}) d\lambda d\beta} \\ &\approx \frac{\sum_{j=0}^N \exp(-n\lambda^{(j)} t_0^{\beta^{(j)}}) I[\lambda^{(j)} \leq -\log(0.95)]}{\sum_{j=0}^N \exp(-n\lambda^{(j)} t_0^{\beta^{(j)}})} \end{aligned}$$

For each n , solve for t_0 .

Weibull Assurance Test Plans



Observations

- ▶ Straightforward generalization to $c > 0$ test plans
- ▶ Similar framework applicable to other test situations: for example, pass/fail or failure count data

Conclusions

- ▶ Science-Based Stockpile Stewardship is a rich source of statistical problems, requiring methodological development in specific problem contexts
- ▶ Example of simultaneous inference within a system reliability representation using multilevel data
- ▶ Reliability assurance methodology provides a formal way to use prior information to develop executable test plans
- ▶ Extension to “resource allocation” for entire system

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